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| Notice of References Cited | Application/Control No. 09/895,353 | Applicant(s)/Patent Under Reexamination AVERY ET AL. | |
| | Examiner Shin-Hon Chen | Art Unit 2131 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| | A | US-6,496,595 | 12-2002 | Puchek et al. | 382/124 |
| | B | US-6,353,853 | 03-2002 | Gravlin, Keith Robert | 709/219 |
| | C | US-2002/0029349 | 03-2002 | DAIGNEAULT et al. | 713/200 |
| | D | US-6,160,903 | 12-2000 | Hamid et al. | 382/115 |
| | E | US-6,281,790 | 08-2001 | Kimmel et al. | 340/506 |
| | F | US-4,689,610 | 08-1987 | Dietrich, William V. | 340/515 |
| | G | US-5,541,585 | 07-1996 | Duhame et al. | 340/5.62 |
| | H | US-6,389,454 | 05-2002 | Ralston et al. | 709/204 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
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with this Office action. (See MPEP § 707.05(a).)
 classifications may be US or foreign.